

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CE0}	40	Vdc
Collector-Base Voltage	V_{CBO}	40	Vdc
Emitter-Base Voltage	V_{EBO}	5.0	Vdc
Collector Current — Continuous	I_C	1.5	Adc
		One Die	All Die Equal Power
Total Device Dissipation @ $T_A = 25^{\circ}\text{C}$	P_D	600	650
Derate above 25°C		350	400
		400	600
		3.42	3.7
		2.0	2.28
		2.28	3.42
Total Device Dissipation @ $T_C = 25^{\circ}\text{C}$	P_D	2.1	3.0
Derate above 25°C		1.25	2.5
		1.0	4.0
		12	17.2
		7.15	14.3
		5.71	22.8
Operating and Storage Junction Temperature Range	T_J, T_{stg}	-65 to +200	
		$^{\circ}\text{C}$	

MD3467,F
MQ3467

MD3467
CASE 654-07, STYLE 1
MD3467F
CASE 610A-04, STYLE 1
MQ3467
CASE 607-04, STYLE 1

DUAL
AMPLIFIER TRANSISTOR

PNP SILICON

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THERMAL CHARACTERISTICS

Characteristic	Symbol	One Die	All Die Equal Power	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	83.3 140 175	58.3 70 43.8	$^{\circ}\text{C/W}$
Thermal Resistance, Junction to Ambient	$R_{\theta JA}(1)$	292 500 438	270 438 292	$^{\circ}\text{C/W}$
Coupling Factors		Junction to Ambient	Junction to Case	%
		85 75 57 55	40 0 0 0	

(1) $R_{\theta JA}$ is measured with the device soldered into a typical printed circuit board.

ELECTRICAL CHARACTERISTICS ($T_A = 25^{\circ}\text{C}$ unless otherwise noted.)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Collector-Emitter Breakdown Voltage(2) ($I_C = 10 \text{ mAdc}, I_B = 0$)	$V_{(BR)CE0}$	40	—	—	Vdc
Collector-Base Breakdown Voltage ($I_C = 10 \text{ } \mu\text{Adc}, I_E = 0$)	$V_{(BR)CBO}$	40	—	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 10 \text{ } \mu\text{Adc}, I_C = 0$)	$V_{(BR)EBO}$	5.0	—	—	Vdc
Collector Cutoff Current ($V_{CB} = 30 \text{ Vdc}, I_E = 0, T_A = 100^{\circ}\text{C}$)	I_{CBO}	—	—	10	μAdc
Emitter Cutoff Current ($V_{BE} = 3.0 \text{ Vdc}, I_C = 0$)	I_{EBO}	—	—	100	nAdc

ELECTRICAL CHARACTERISTICS (continued) ($T_A = 25^\circ\text{C}$ unless otherwise noted.)

Characteristic	Symbol	Min	Typ	Max	Unit
ON CHARACTERISTICS					
DC Current Gain ($I_C = 500\text{ mAdc}$, $V_{CE} = 1.0\text{ Vdc}$)	h_{FE}	20	—	—	—
Collector-Emitter Saturation Voltage ($I_C = 500\text{ mAdc}$, $I_B = 50\text{ mAdc}$)	$V_{CE(sat)}$	—	0.32	0.5	Vdc
Base-Emitter Saturation Voltage ($I_C = 500\text{ mAdc}$, $I_B = 50\text{ mAdc}$)	$V_{BE(sat)}$	—	0.95	1.2	Vdc
SMALL-SIGNAL CHARACTERISTICS					
Current-Gain — Bandwidth Product ($I_C = 50\text{ mAdc}$, $V_{CE} = 10\text{ Vdc}$; $f = 100\text{ MHz}$)	f_T	150	220	—	MHz
Output Capacitance ($V_{CB} = 10\text{ Vdc}$, $I_E = 0$, $f = 140\text{ kHz}$)	C_{obo}	—	8.5	20	pF
Input Capacitance ($V_{BE} = 0.5\text{ Vdc}$, $I_C = 0$, $f = 140\text{ kHz}$)	C_{ibo}	—	22	80	pF
SWITCHING CHARACTERISTICS					
Delay Time ($V_{CC} = 30\text{ Vdc}$, $V_{BE} = 2.0\text{ Vdc}$, $I_C = 500\text{ mAdc}$, $I_{B1} = 50\text{ mAdc}$)	t_d	—	7.0	10	ns
Rise Time ($V_{CC} = 30\text{ Vdc}$, $V_{BE} = 2.0\text{ Vdc}$, $I_C = 500\text{ mAdc}$, $I_{B1} = 50\text{ mAdc}$)	t_r	—	17	30	ns
Storage Time ($V_{CC} = 30\text{ Vdc}$, $I_C = 500\text{ mAdc}$, $I_{B1} = I_{B2} = 50\text{ mAdc}$)	t_s	—	58	80	ns
Fall Time ($V_{CC} = 30\text{ Vdc}$, $I_C = 500\text{ mAdc}$, $I_{B1} = I_{B2} = 50\text{ mAdc}$)	t_f	—	14	30	ns

(2) Pulse Test: Pulse Width $\leq 300\text{ }\mu\text{s}$, Duty Cycle $\leq 2.0\%$.

FIGURE 1 — DC CURRENT GAIN

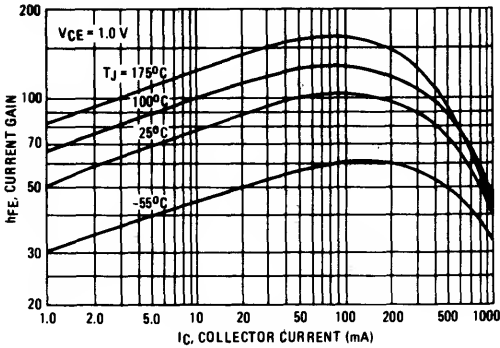


FIGURE 2 — COLLECTOR SATURATION REGION

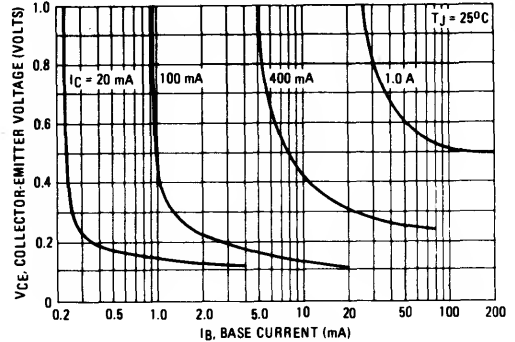


FIGURE 3 — "ON" VOLTAGE

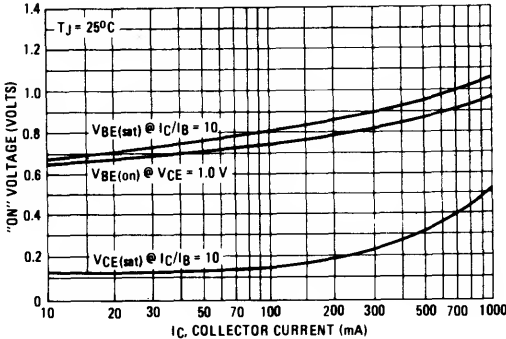


FIGURE 4 — TEMPERATURE COEFFICIENTS

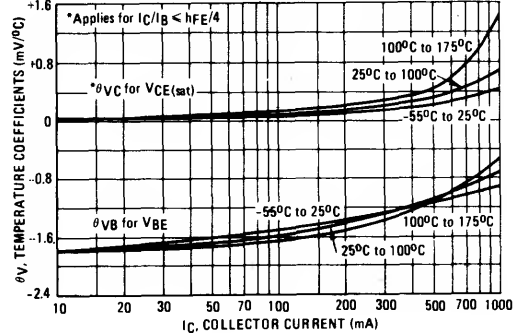


FIGURE 5 – ACTIVE REGION SAFE OPERATING AREA

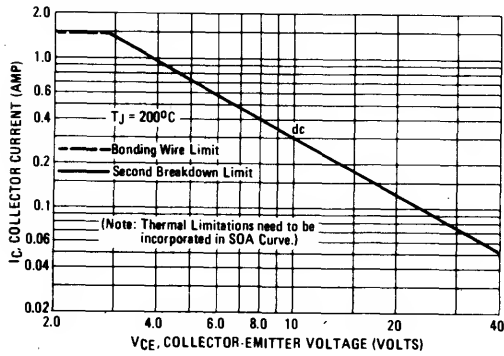


FIGURE 6 – TURN-ON TIME

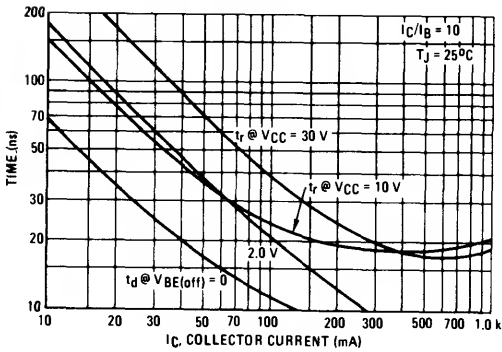


FIGURE 7 – RISE AND FALL TIME

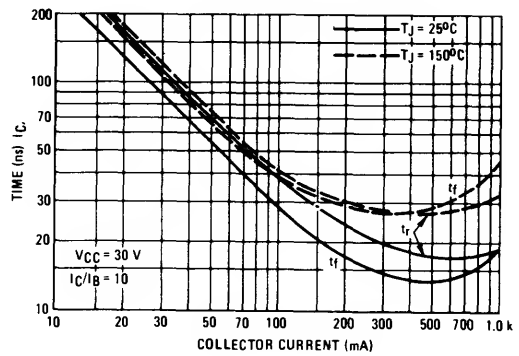


FIGURE 8 – STORAGE TIME

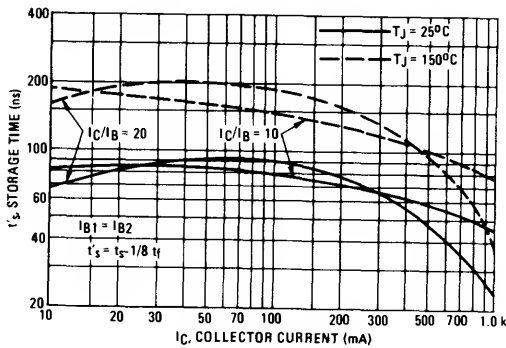


FIGURE 9 – FALL TIME

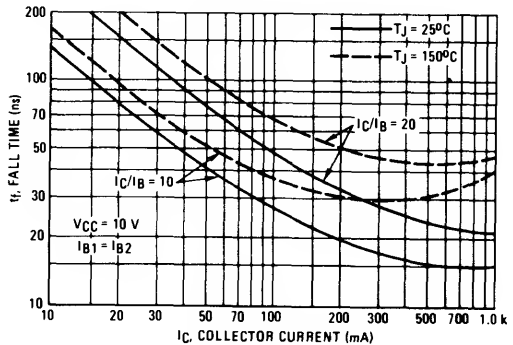


FIGURE 10 – SWITCHING TIME TEST CIRCUIT

$I_C = 500 \text{ mA}$
 $I_{B1} = I_{B2} = 50 \text{ mA}$
Rise Time $\leq 5 \text{ ns}$
Pulse Width = $0.5 \mu\text{s}$
Duty Cycle = 2%

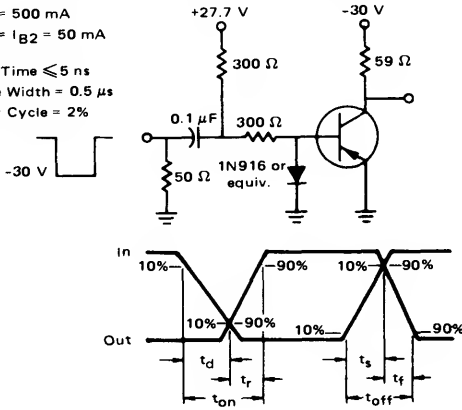


FIGURE 11 – CAPACITANCE

